

ABSTRACT OF THE DISCLOSURE

A high frequency dithering probe for a high speed scanning probe microscope includes a high frequency quartz-crystal resonator having a
5 fundamental resonant frequency in the range of 1MHz ~100MHz and a thickness of 0.01mm~2.0mm, an electrode attached to the quartz-crystal resonator, and a probe attached to the quartz-crystal resonator. With the high frequency dithering probe having the improved scanning speed, a test sample can be observed within a short time and an object being changed can be also observed.

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